

# Friction and Surface Deformation in Electrodeposited Gold Alloy Thin Films

John M. Jungk, Somuri V. Prasad and Michael T Dugger

Department of Microsystem Materials

Sandia National Laboratories

*2006 STLE Annual Meeting*

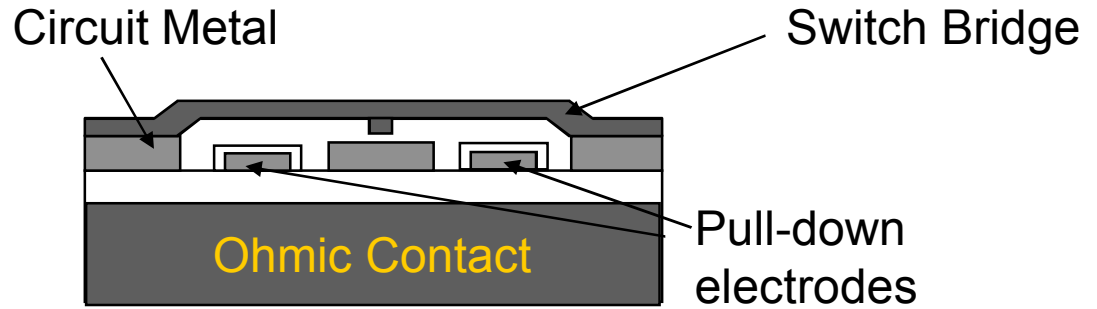
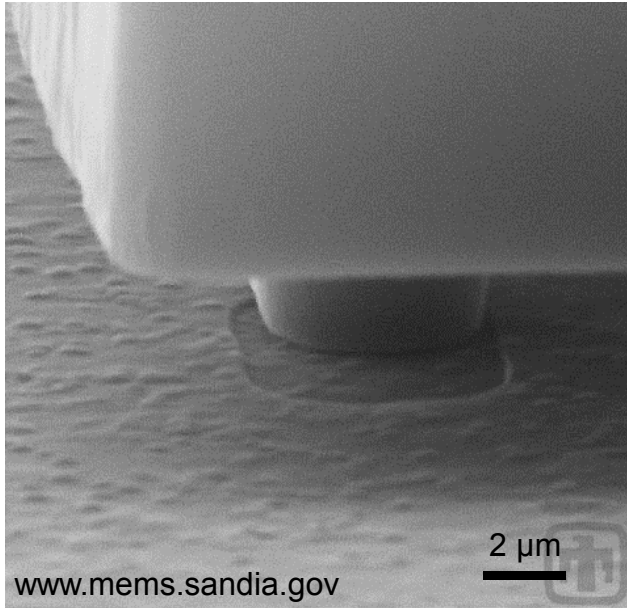
*May 7-12*

*Calgary, AB*



- **Motivation and Overview**
  - **Hard gold films as electrical contact surfaces**
  - **Friction vs. microstructure issues**
- **Experimental results**
  - **Linear wear testing**
  - **FEM simulations**
  - **Current/Future work**
- **Conclusions**

# Ohmic Microsystem Contacts



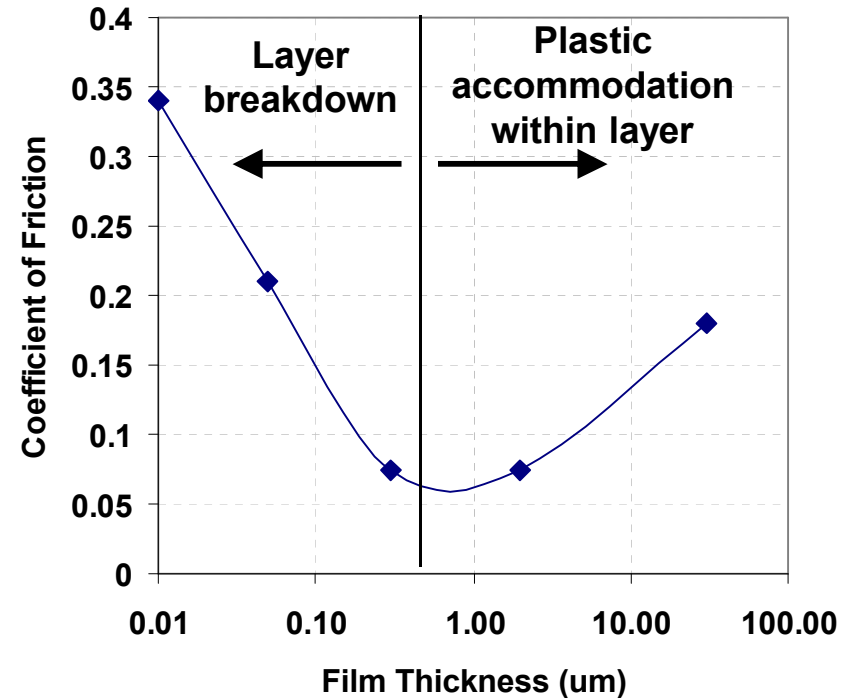
**The ideal electrical contact interface would include:**

- 1) Low electrical resistance**
- 2) Minimal adhesion [D. Dickrell – 8G]**
- 3) Low friction (sliding contact)**



# Contribution of Bowden and Tabor

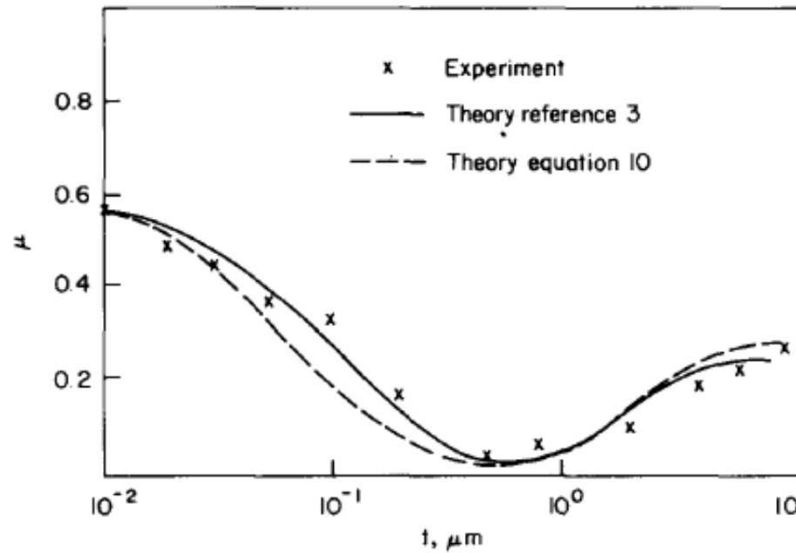
- Hard materials have high shear strengths
  - High frictional coefficients
- Low shear strength metals are usually soft
  - Large contact areas
- Solution is to use a layered system
  - Thin film of soft metal over substrate of hard metal



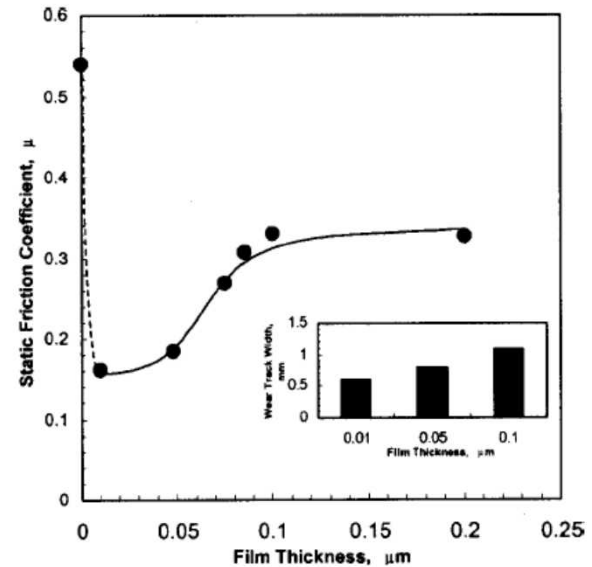
**Thickness of film can greatly influences the overall tribological response of a system**

# Other material systems

## lead on steel

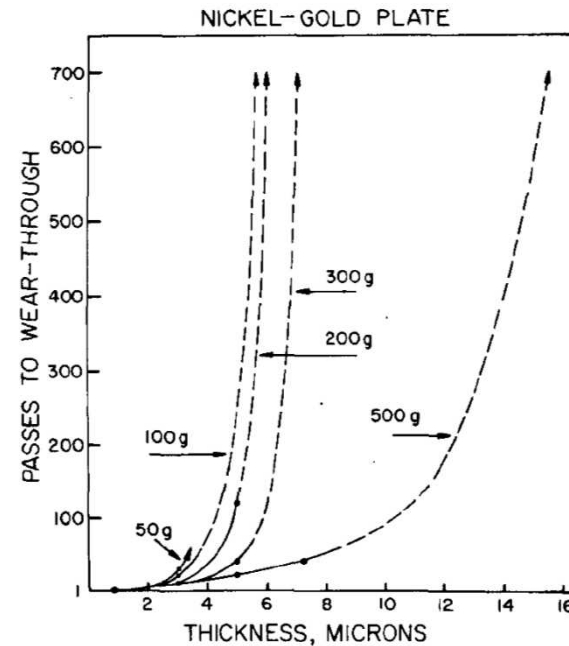
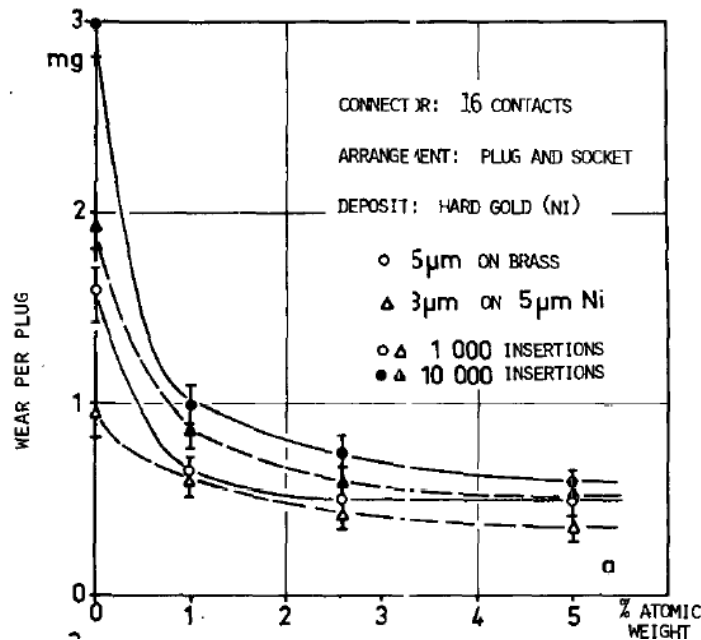


## silver on steel



- Behaviors of lead and silver on hardened steels
  - Hard substrate with low shear strength coating is the key

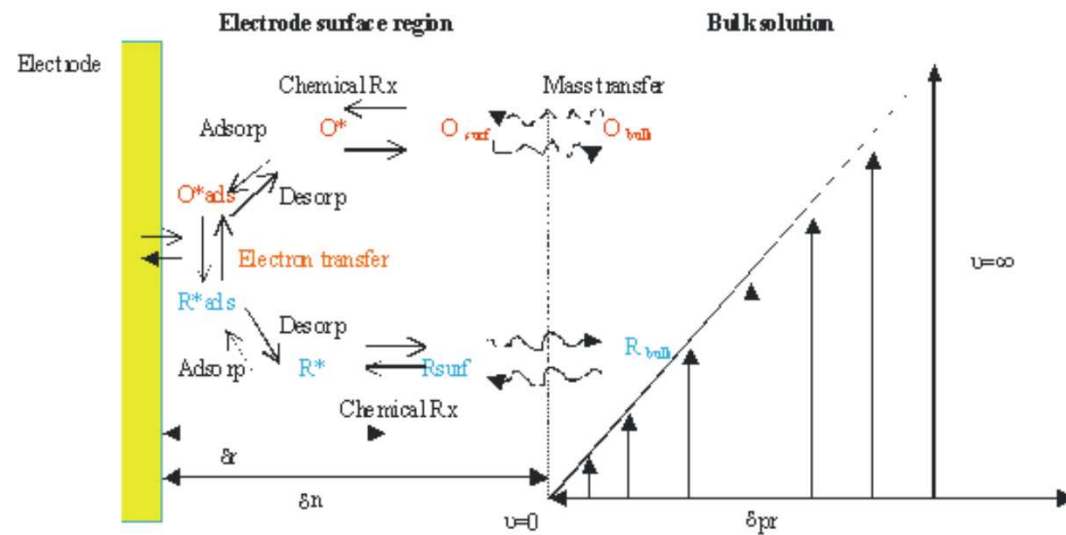
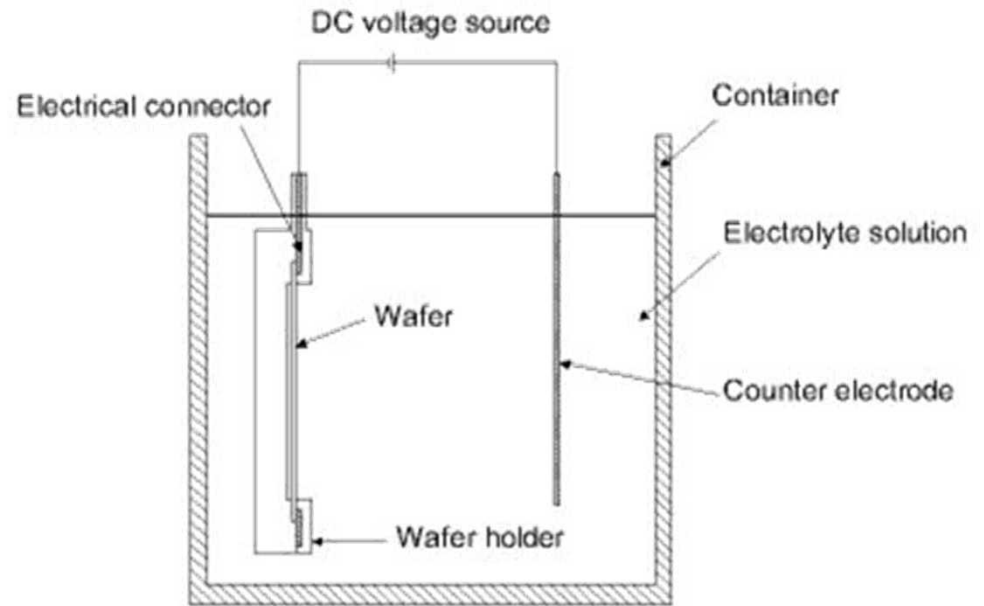
# Variables of Electroplated Gold



- Additives intentionally included into the films
  - Improves wear resistance
- Film thickness is related to wear-through

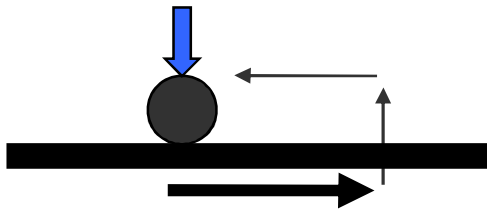
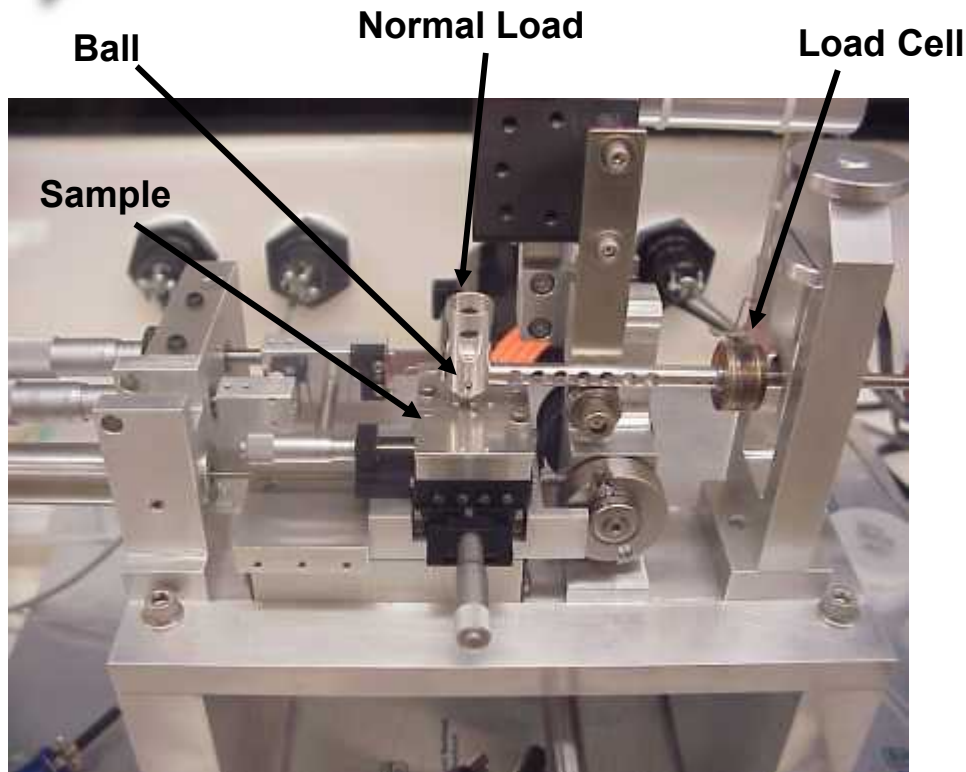
# Electrodeposition of Hard Gold

- **Typical Additives**
  - Nickel, Cobalt, polymer, thorium
  - Goal is grain refinement (and SS hardening)
- **Bath electrolytes**
  - Free-cyanide base
  - Thiosulfate complex
- **ASTM and/or MIL-G-45204**
  - Hardness ranges





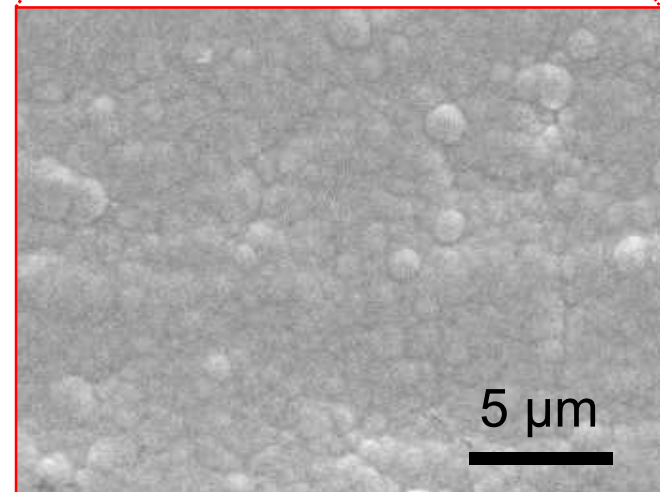
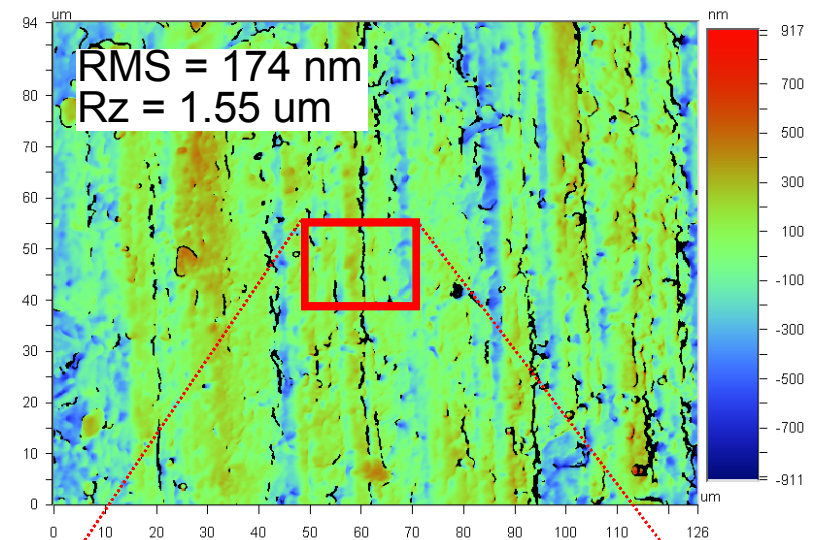
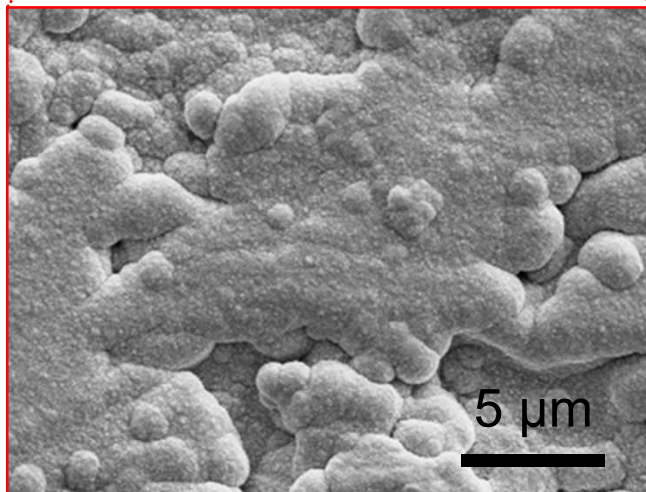
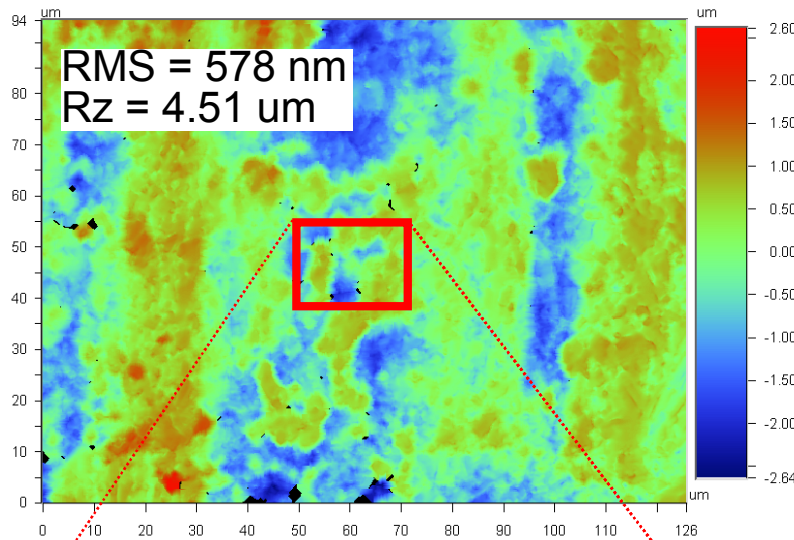
# Linear Wear Testing



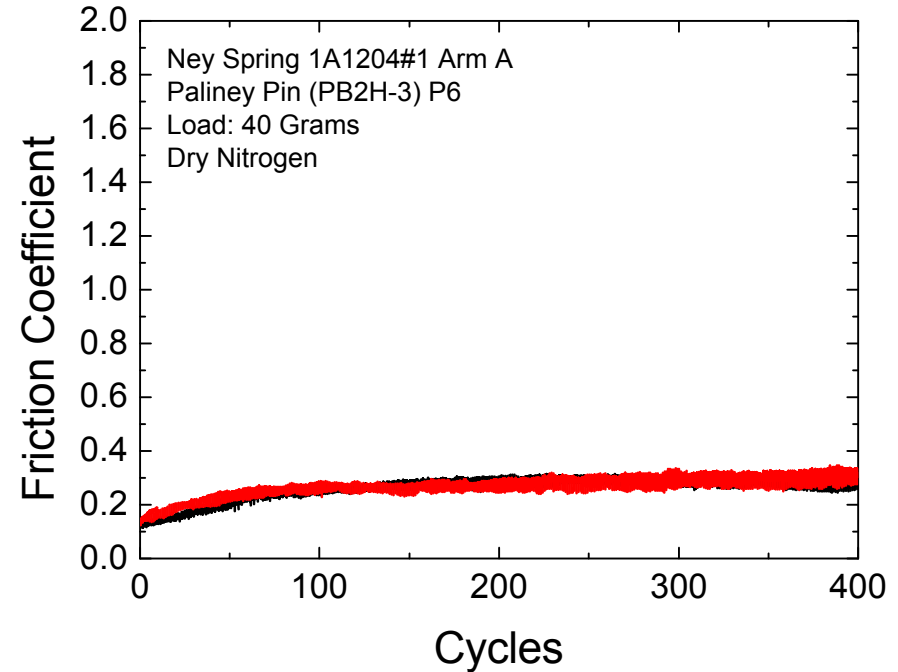
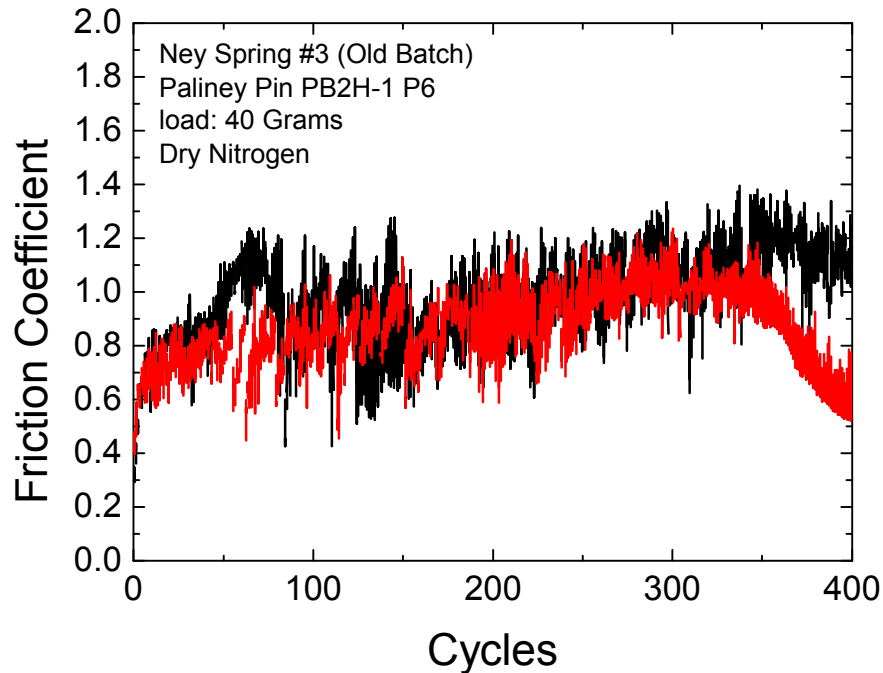
- Creates a unidirectional linear (wiping) motion across the sample
- Typical test conditions
  - 1/8"  $\text{Si}_3\text{N}_4$  ball
  - 380  $\mu\text{m}$  Paliney Pin
  - 40 Hz
  - 1000 cycles
- Controlled Atmosphere
  - $\text{O}_2 < 10$  ppm
  - Dew point  $< -35$  °C



# Grain size and roughness of Hard Gold

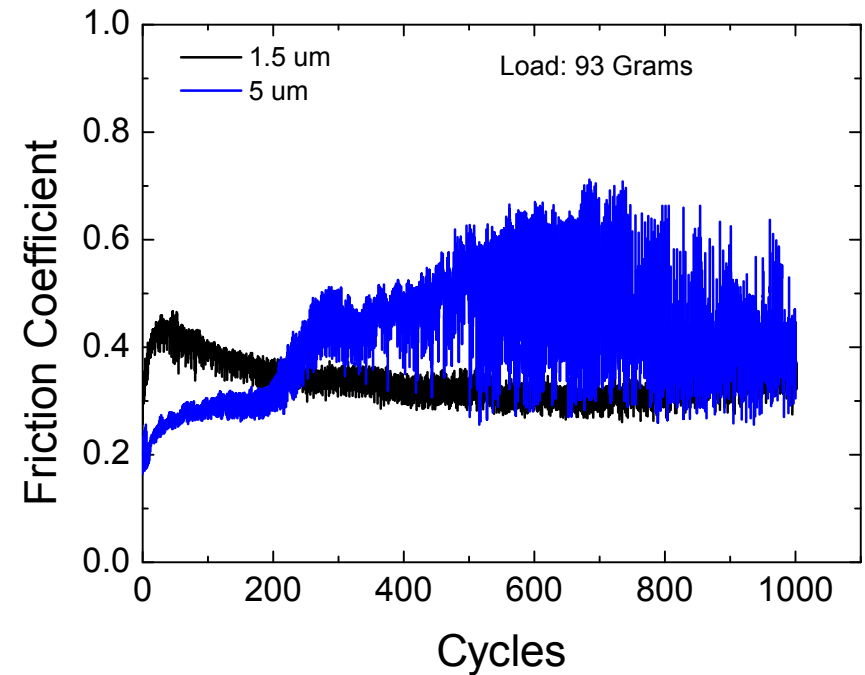
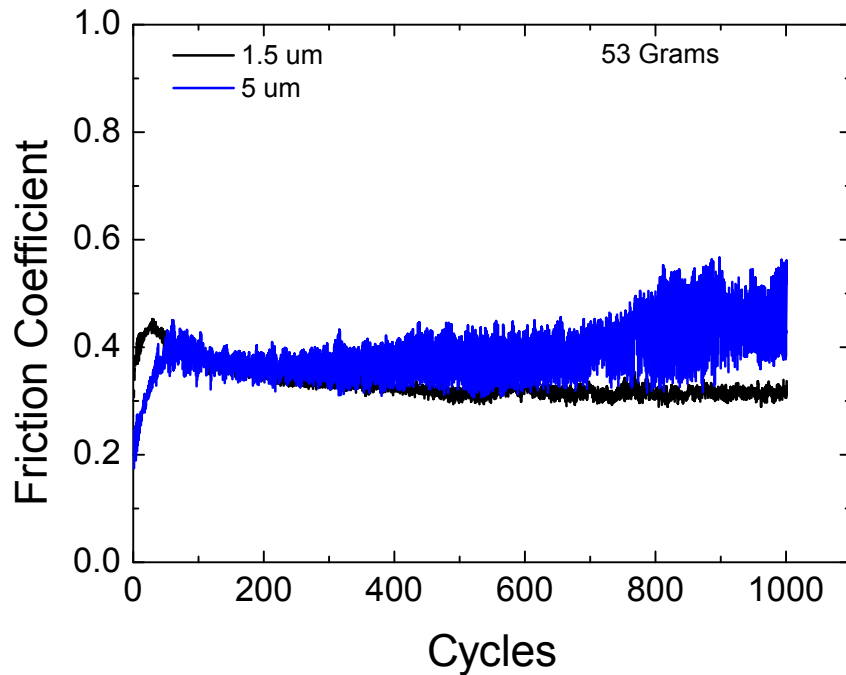


# Grain Size Effects



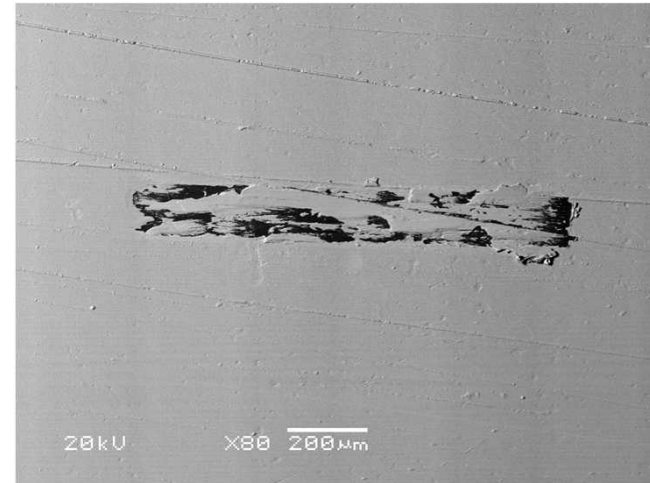
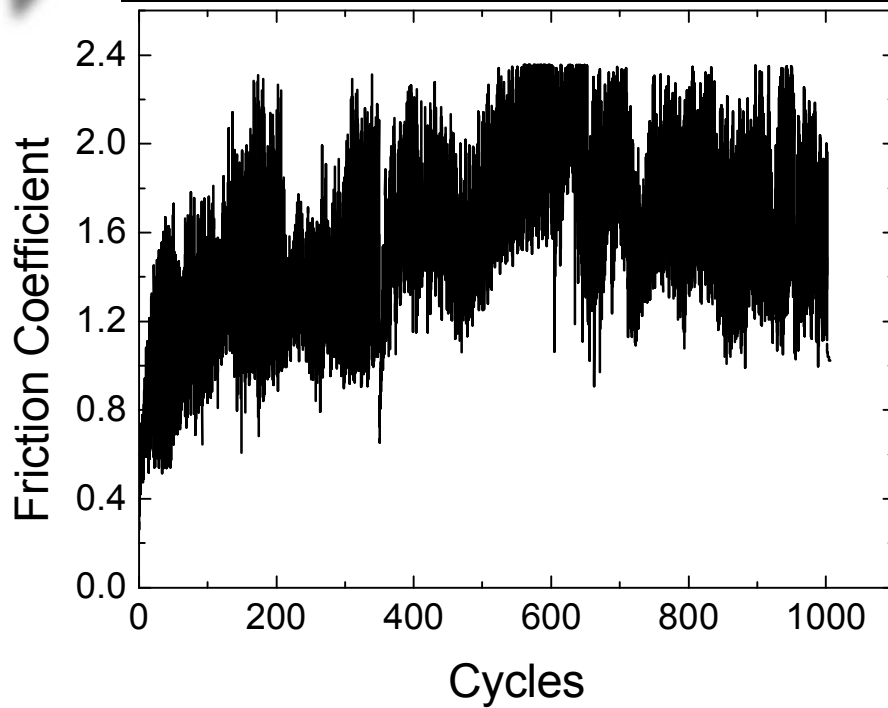
- Nominally identical films (chemically)
- Larger grain size shows much greater frictional coefficient

# Hard Gold Thickness Effects

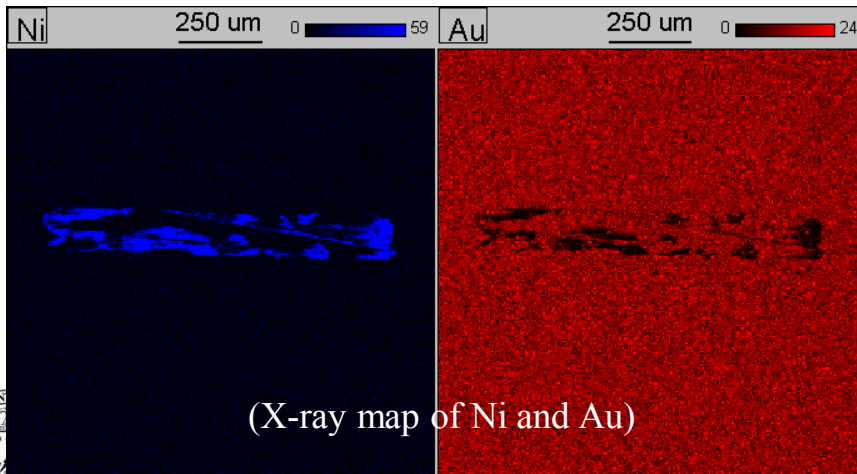


- Counterface – Paliney Pin (380  $\mu\text{m}$  radius)
- Increasing the gold thickness changes frictional coefficient
  - Large fluctuations due to ...film deformation (grooving)

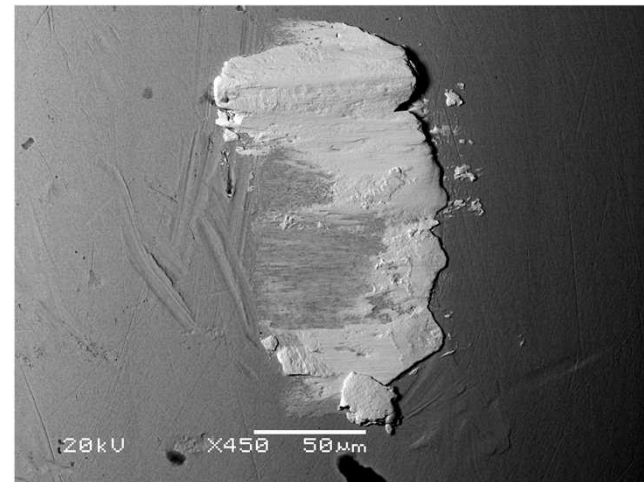
# Soft Gold Friction Testing



(Backscatter image of wear scar)



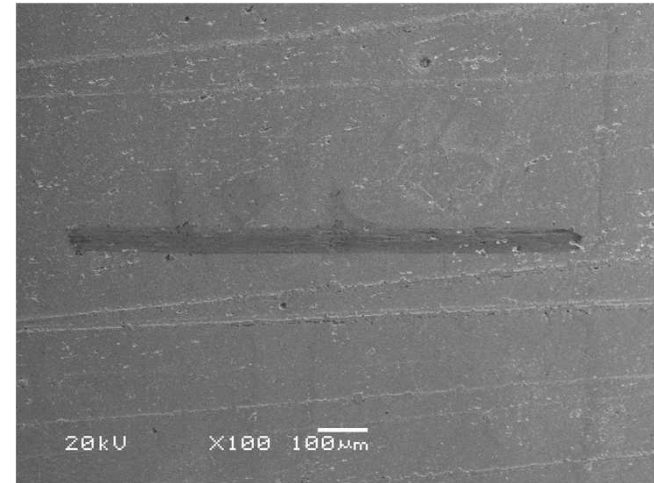
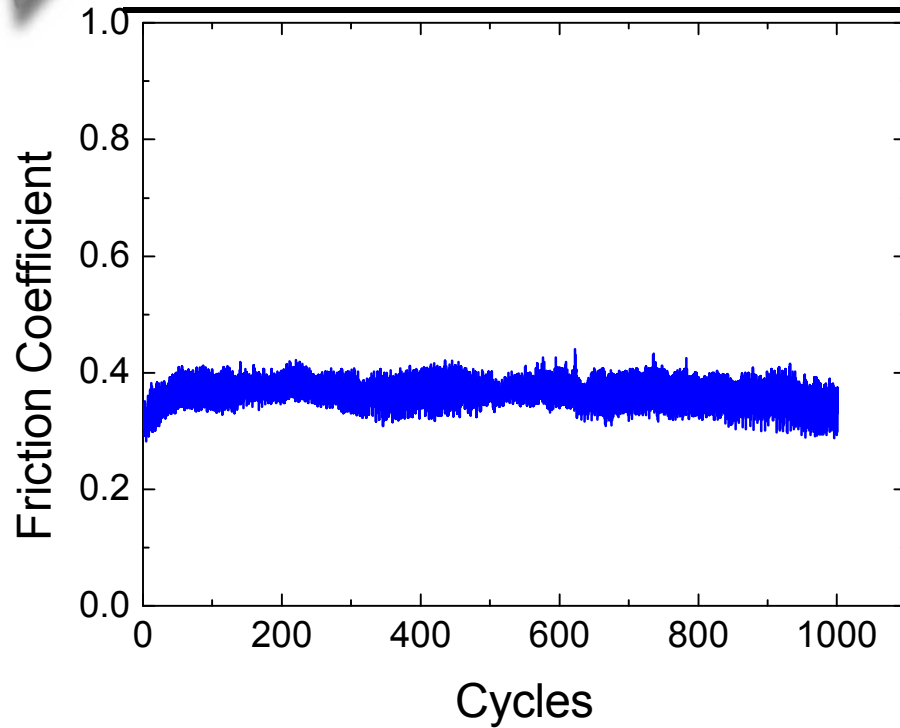
(X-ray map of Ni and Au)



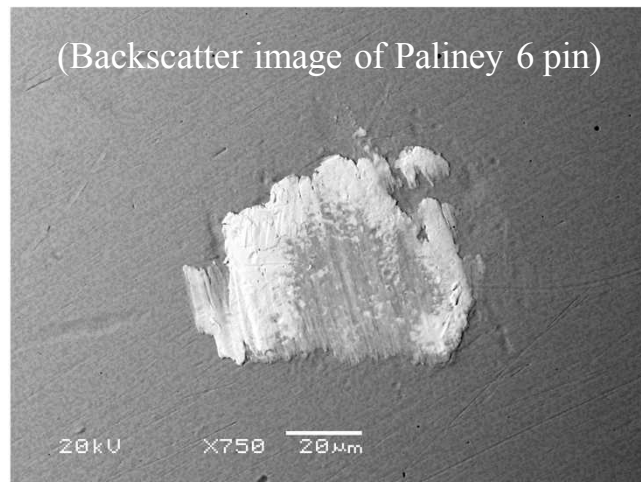
(Backscatter image of Paliney 6 pin)



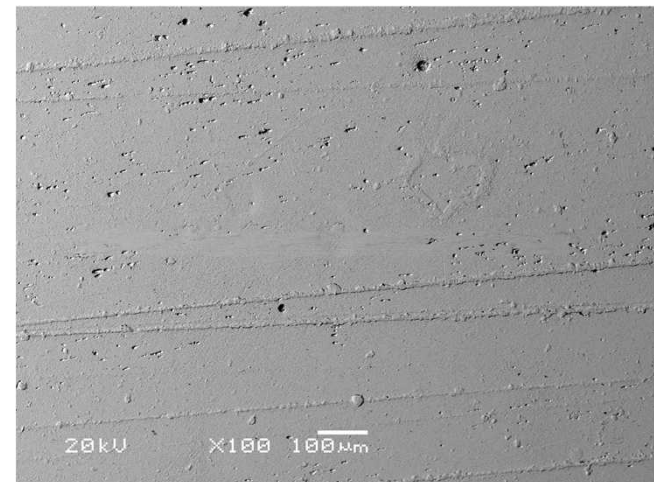
# Hard Gold Friction Testing



(SEM image of wear scar)

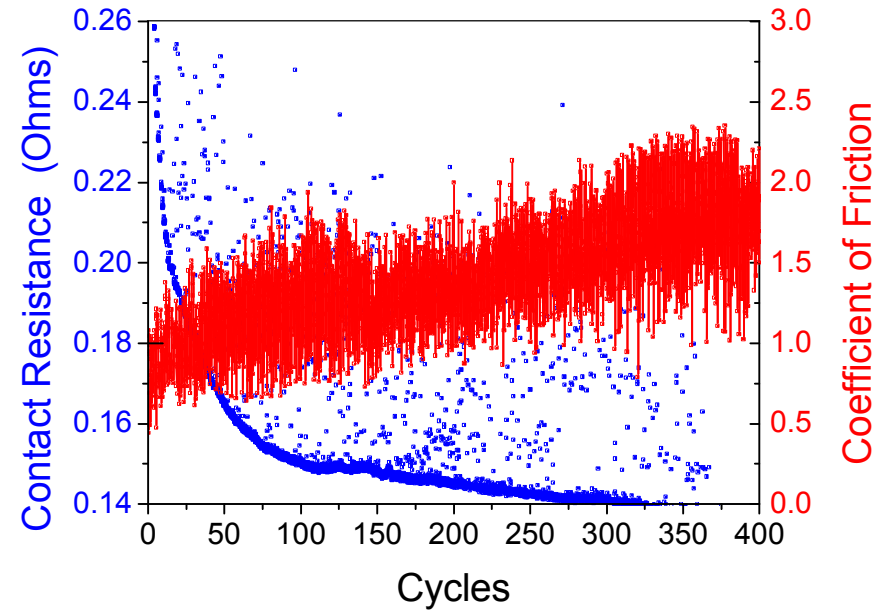
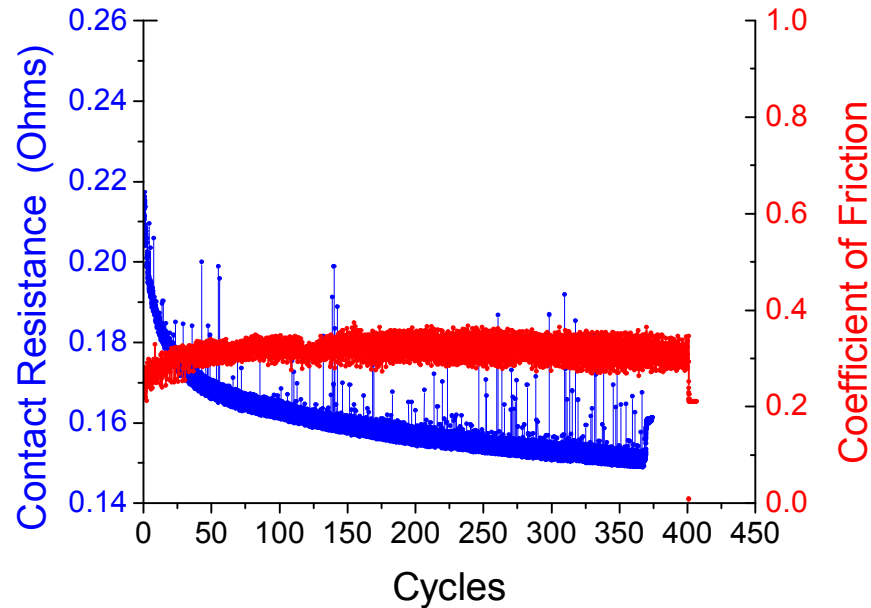


(Backscatter image of Paliney 6 pin)



(Backscatter image of wear scar)

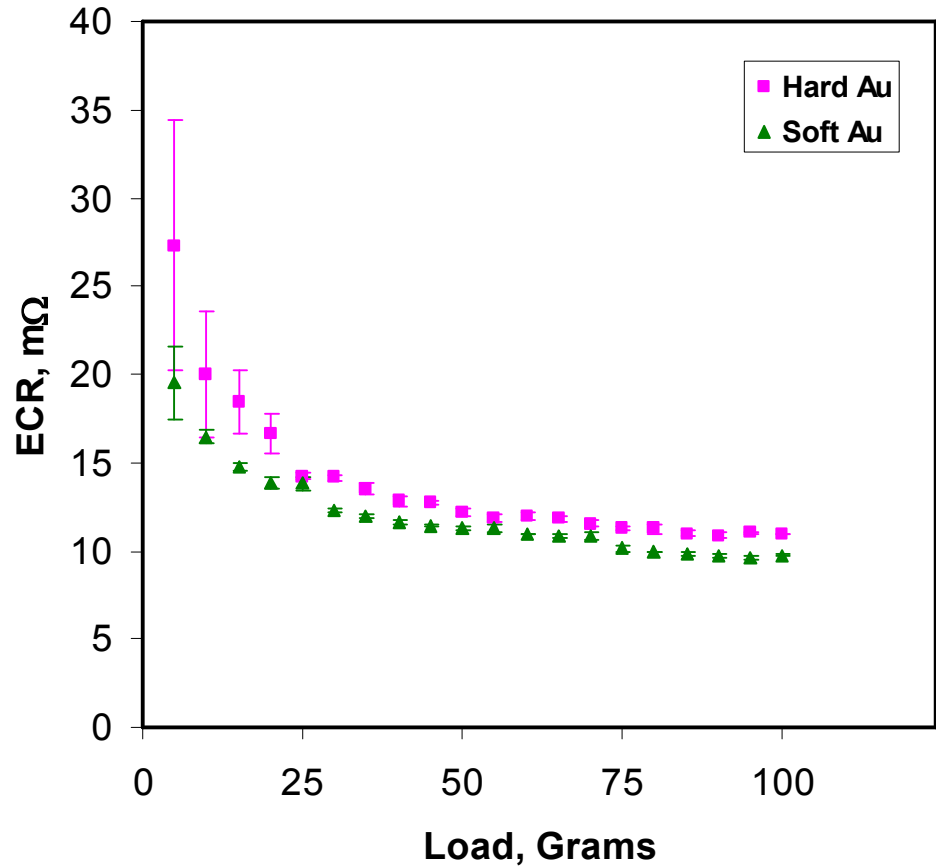
# Hard Gold and Sliding Contact Resistance



- **Paliney Pin**
  - 50 mN load (5 grams)
- **Similar contact resistance values even with greatly different frictional coefficients**

# ECR and Static Load

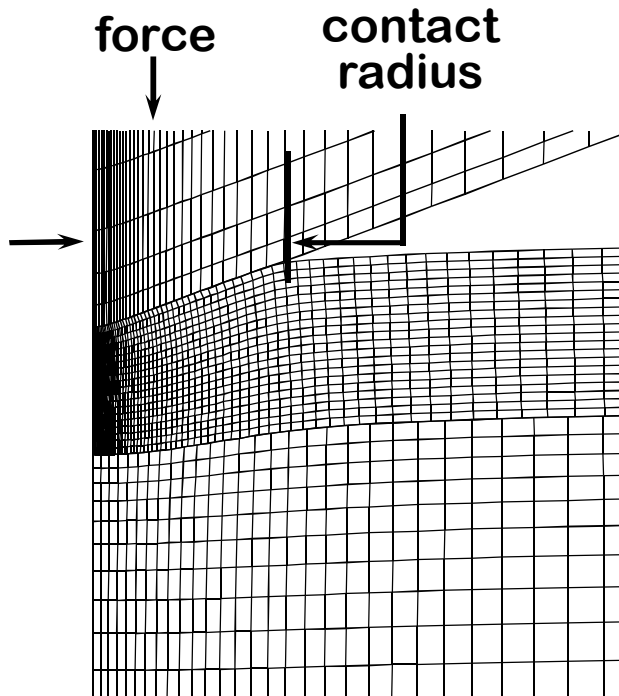
- Contact resistance related to applied load
- Contact area





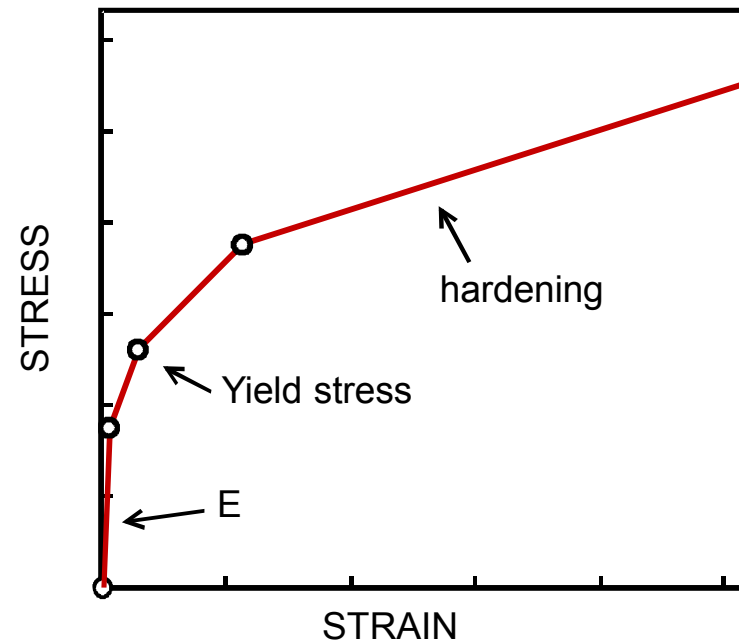
# Modeling of Contact

- Meshes are generated specific to each sample, including layer thickness and pin shape.
- Specific material properties are assigned to each component in the mesh

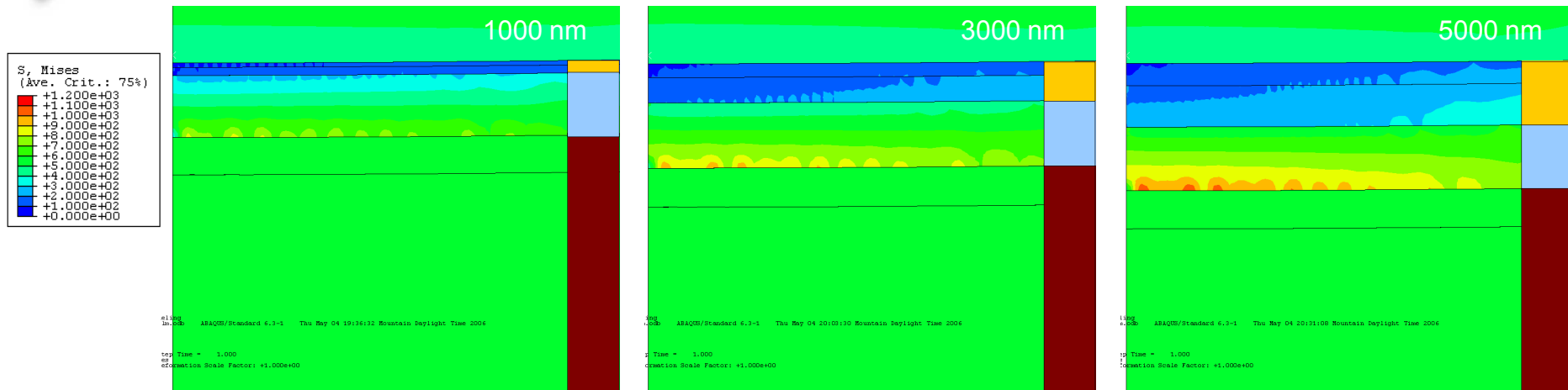


2D axisymmetric mesh

$$\sigma = E\varepsilon \quad \text{for } \varepsilon < Y_0/E$$
$$\sigma = K\varepsilon^n \quad \text{for } \varepsilon \geq Y_0/E$$

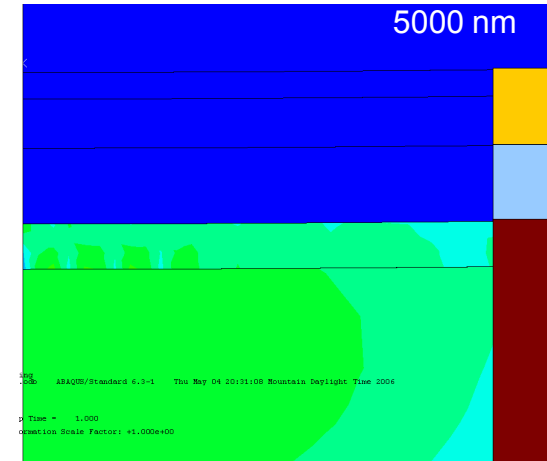
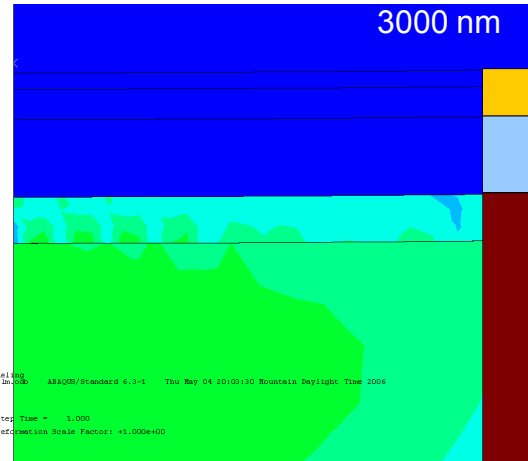
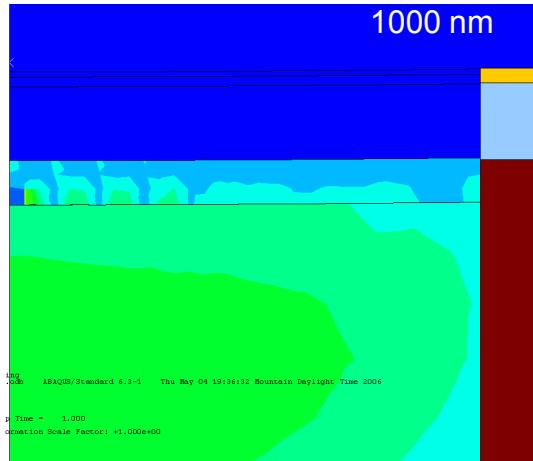
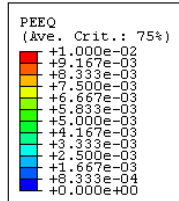


# Mises Stress – Large Pin (R = 1600 $\mu\text{m}$ )



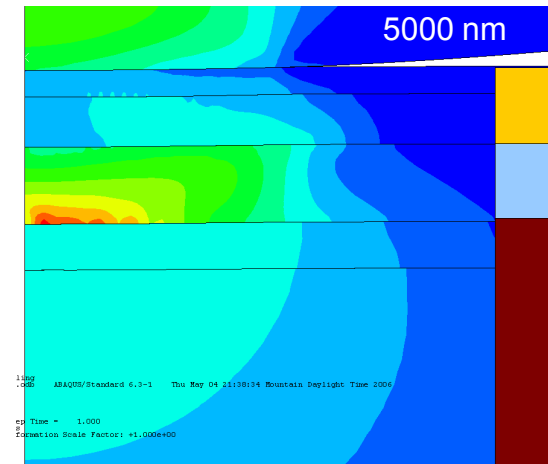
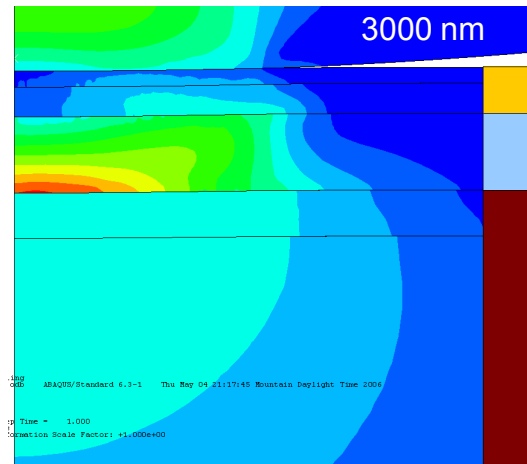
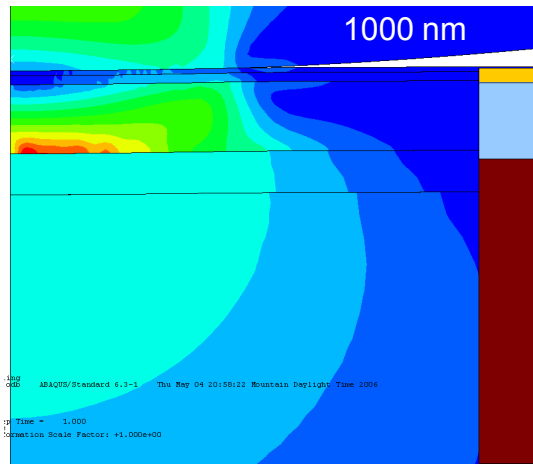
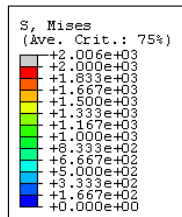
- Large probe distributes the load
  - Regions of peak stress are relatively deep in the substrate
- Majority of the stress is carried by the stiffer (and harder) nickel and Alloy52

# Plastic Strain – Large Pin (R = 1600 $\mu\text{m}$ )



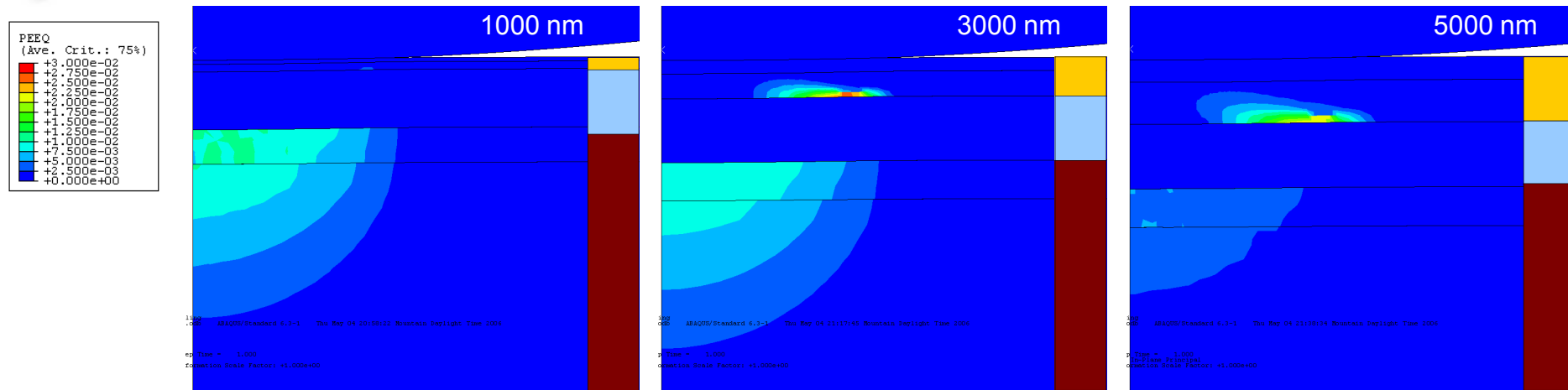
- Plasticity is limited to substrate
- Depth of peak stress is ~ 20 microns

# Mises Stress – Medium Pin (R = 400 $\mu\text{m}$ )



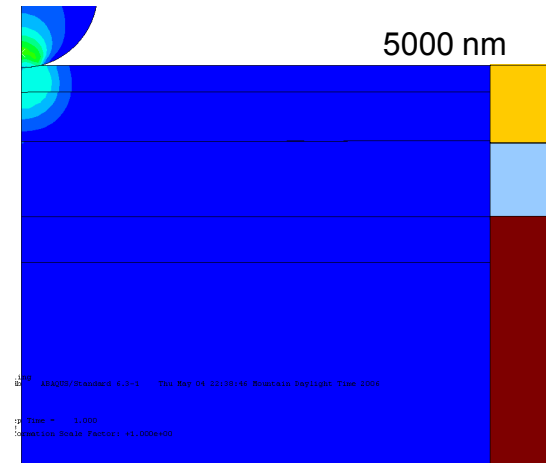
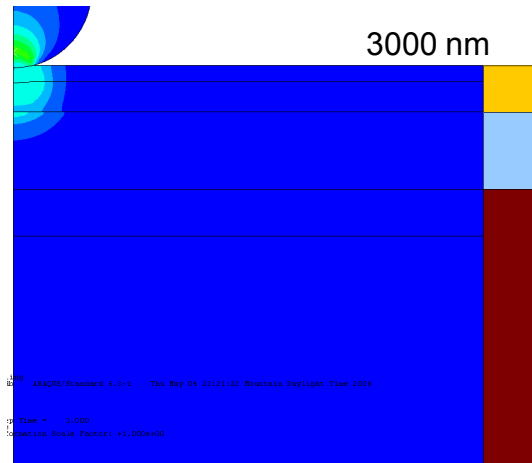
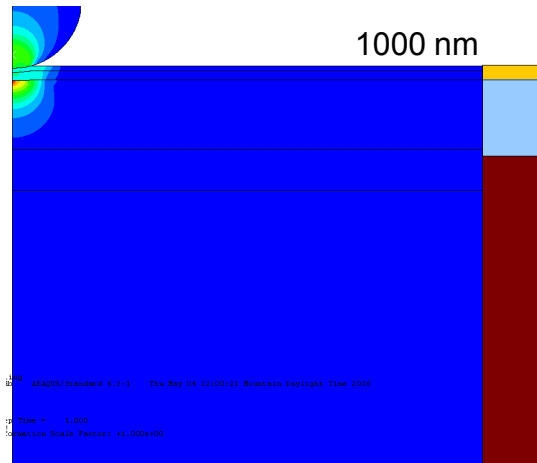
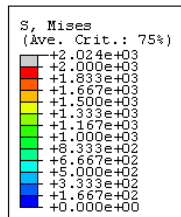
- The stresses distribute based on the elastic properties of the layers
  - Increasing layer thickness allows the gold to carry more of the load
- Stresses are highest in the nickel plating

# Plastic Strain – Medium Pin (R = 400 $\mu\text{m}$ )



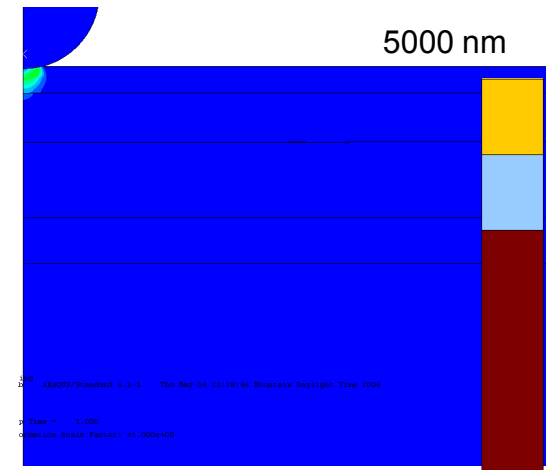
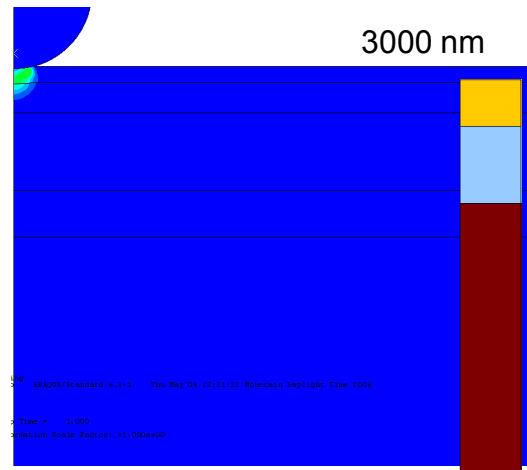
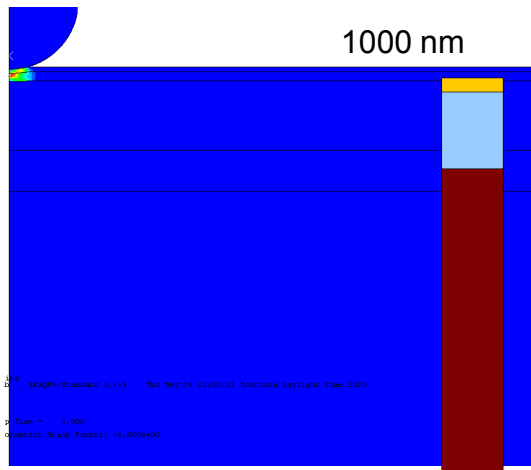
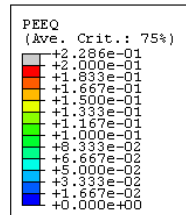
- Thickening of gold film moves the location of peak (Hertzian) shear towards the gold coating
  - Results in zone of plastic deformation entering gold film
- Plastic deformation within the film may lead to grooving and increase frictional coefficients

# Mises Stress – Small Pin ( $R = 5 \mu\text{m}$ )



- $5 \mu\text{m} \sim \text{MEMS scale contact}$
- Confined stresses
  - But localized in the near-surface
  - Small probe tip results in large stress gradients

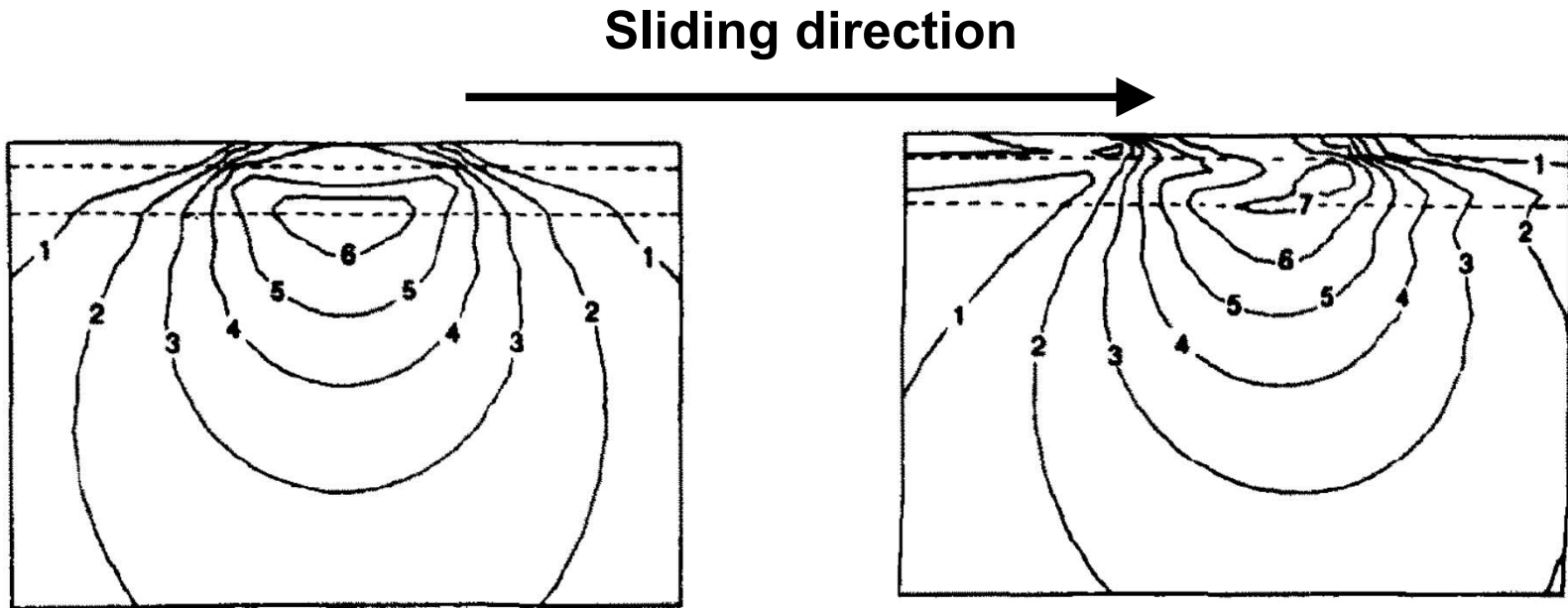
# Plastic Strain – Small Pin ( $R = 5\ \mu\text{m}$ )



- Film in all cases is plastically deformed through the thickness
- Plasticity is truncated at the (harder) nickel interface



# Shift in contour due to sliding



- Sliding shifts the stress contours towards the surface
  - Brings peak shear closer to the gold coating
  - Increases likelihood of plastic flow (and subsequent grooving) in gold film

- **Hard gold coatings are useful as functional electrical contacts for sliding applications**
  - **Reduce friction by a factor of  $\sim 3$**
- **Thickness of the coating dictates (in part) the sliding stresses**
- **FEM implies that increase in frictional coefficient is due to peak shear moving into the gold coating**
  - **Smaller (sharper) pins move peak shear towards (and into) Au film**



# Acknowledgements and Questions

---

## **Sandia National Laboratories**

James Knapp

Aaron Ison

Rand Garfield

Elizabeth Huffman

Alice Kilgo

**Questions?**

## **University of Florida**

Dan Dickrell

## **Silvex Surface Technology, Inc**

Tom Wefers

